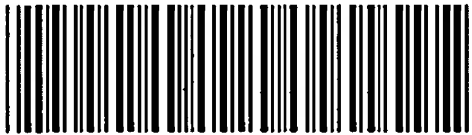


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/695,244	CHIN ET AL.	
	Examiner	Art Unit	
	Hsien-ming Lee	2823	

SEARCHED			
Class	Subclass	Date	Examiner
438	106,110	5/31/2005	LEE
438	113, 460	↓	↓
438	463,464	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAS <sub>t</sub> attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	5/31/2005	LEE